课程代码（Coursenumber）：
208.

课程名（Coursename）：
Structure Analysis by X-Ray Diffraction.

学分（credit) ：(4)

课程设置（course setting）：Two one-hour lectures and two four-hour
laboratories per week.

选课要求（prerequisite）：Consent of instructor.

课程描述（Description）：The theory and practice of modern, single-crystal X-ray diffraction. Groups of four students determine the crystal and molecular structure of newly synthesized materials from the College of Chemistry. The laboratory work involves the mounting of crystals
and initial evaluation by X-ray diffraction film techniques, the collection
of intensity data by automated diffractometer procedures, and structure
analysis and refinement. (S)

教参信息（Textbookinfo）:
1 Crystal Structure Analysis: A Primer by Jenny P. Glusker and Kenneth N. Trueblood (Paperback - Aug. 29, 1985)
ISBN-13: 978-0195035438
2 Structure Determination by X-Ray Crystallography by Mark F.C. Ladd and Rex A. Palmer (Paperback - Sept. 30, 2003)
ISBN-13: 978-0306474545
世界各地拥有馆藏的图书馆（OCLC）:191
3 Electron Density and Bonding in Crystals: Principles, Theory and X-Ray Diffraction Experiments in Solid State Physics and Chemistry by V. G. Tsirelson and R. P. Ozerov (Hardcover - Jan. 1, 1996)
ISBN-13: 978-0750302845
4 Crystal Structure Analysis for Chemists and Biologists (Methods in Stereochemical Analysis) by Jenny P. Glusker, Mitchell Lewis, and Miriam Rossi (Hardcover - Aug. 1994)
ISBN-13: 978-0471185437
5 Two-dimensional X-ray Diffraction by Bob B. He (Hardcover - Aug. 10, 2009)
ISBN-13: 978-0470227220
世界各地拥有馆藏的图书馆（OCLC）:117
6 Crystallography Made Crystal Clear, Third Edition: A Guide for Users of Macromolecular Models (Complementary Science) by Gale Rhodes (Paperback - Mar. 2, 2006)
ISBN-13: 978-0125870733
世界各地拥有馆藏的图书馆（OCLC）:229
7 Thin Film Analysis by X-Ray Scattering by Mario Birkholz (Hardcover - Feb. 6, 2006)
ISBN-13: 978-3527310524
世界各地拥有馆藏的图书馆（OCLC）:136
8 Anomalous X-Ray Scattering for Materials Characterization (Springer Tracts in Modern Physics) by Yoshio Waseda (Hardcover - Oct. 3, 2002)
ISBN-13: 978-3540434436
世界各地拥有馆藏的图书馆（OCLC）:167
9 Advances in X-Ray Analysis, Vol. 35 by C.S. Barrett, John V. Gilfrich, Ting C. Huang, and Ron Jenkins (Hardcover - Oct. 31, 1992)
ISBN-13: 978-0306442490
10 Industrial Applications of X-Ray Diffraction by Frank Smith (Hardcover - Sept. 22, 1999)
ISBN-13: 978-0824719920